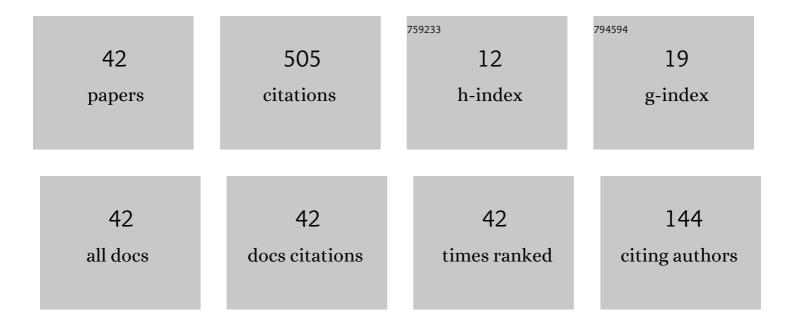
Diego Vazquez Garcia De La Vega

List of Publications by Year in descending order

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#	Article	IF	CITATIONS
1	Energy-Aware Low-Power CMOS LNA with Process-Variations Management. Active and Passive Electronic Components, 2016, 2016, 1-10.	0.3	Ο
2	A Proposal for Yield Improvement with Power Tradeoffs in CMOS LNAs. IEEE Latin America Transactions, 2016, 14, 13-19.	1.6	2
3	On-chip sinusoidal signal generation with harmonic cancelation for analog and mixed-signal BIST applications. Analog Integrated Circuits and Signal Processing, 2015, 82, 67-79.	1.4	28
4	Analysis of process variations' impact on a 2.4 GHz 90 nm CMOS LNA. , 2013, , .		1
5	Sinusoidal signal generation for mixed-signal BIST using a harmonic-cancellation technique. , 2013, , .		7
6	A 3.6mW @ 1.2V high linear 8 th -order CMOS complex filter for IEEE 802.15.4 standard. , 2011, , .		5
7	Analog Sinewave Signal Generators for Mixed-Signal Built-in Test Applications. Journal of Electronic Testing: Theory and Applications (JETTA), 2011, 27, 305-320.	1.2	10
8	2.4-GHz single-ended input low-power low-voltage active front-end for ZigBee applications in 90 nm CMOS. , 2011, , .		14
9	A BIST Solution for Frequency Domain Characterization of Analog Circuits. Journal of Electronic Testing: Theory and Applications (JETTA), 2010, 26, 429-441.	1.2	5
10	Low-cost signature test of RF blocks based on envelope response analysis. , 2010, , .		6
11	On-chip characterisation of RF systems based on envelope response analysis. Electronics Letters, 2010, 46, 36.	1.0	9
12	Guidelines for the efficient design of sinewave generators for analog/mixed-signal BIST. , 2010, , .		3
13	A BIST Solution for the Functional Characterization of RF Systems Based on Envelope Response Analysis. , 2009, , .		4
14	Practical test cores for the on-chip generation and evaluation of analog test signals: Application to a network/spectrum analyzer for analog BIST. , 2009, , .		1
15	Efficient functional built-in test for RF systems using two-tone response envelope analysis. , 2009, , .		2
16	Practical Implementation of a Network Analyzer for Analog BIST Applications. , 2008, , .		1
17	A 2.4GHz LNA in a 90-nm CMOS technology designed with ACM model. , 2008, , .		2
18	Practical implementation of a network analyzer for analog BIST applications. , 2008, , .		2

Practical implementation of a network analyzer for analog BIST applications. , 2008, , . 18

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#	Article	IF	CITATIONS
19	A 1.2V 5.14mW quadrature frequency synthesizer in 90nm CMOS technology for 2.4GHz ZigBee applications. , 2008, , .		7
20	A Sinewave Analyzer for Mixed-Signal BIST Applications in a 0.35 um Technology. , 2006, , .		4
21	On-Chip Analog Sinewave Generator with Reduced Circuitry Resources. Midwest Symposium on Circuits and Systems, 2006, , .	1.0	12
22	Test of switched-capacitor ladder filters using OBT. Microelectronics Journal, 2005, 36, 1073-1079.	2.0	21
23	A low-cost digital frequency testing approach for mixed-signal devices using ΣΔ modulation. Microelectronics Journal, 2005, 36, 1080-1090.	2.0	17
24	Sine-Wave Signal Characterization Using Square-Wave and ??-Modulation: Application to Mixed-Signal BIST. Journal of Electronic Testing: Theory and Applications (JETTA), 2005, 21, 221-232.	1.2	14
25	A Switched Opamp-Based Bandpass Filter: Design and Implementation in a 0.35 μm CMOS Technology. Analog Integrated Circuits and Signal Processing, 2003, 34, 201-209.	1.4	1
26	Oscillation-based test in bandpass oversampled A/D converters. Microelectronics Journal, 2003, 34, 927-936.	2.0	21
27	LP-LV high-performance monolithic DTMF receiver with on-chip test facilities. , 2003, , .		2
28	Practical oscillation-based test of integrated filters. IEEE Design and Test of Computers, 2002, 19, 64-72.	1.0	67
29	Testing mixed-signal cores: a practical oscillation-based test in an analog macrocell. IEEE Design and Test of Computers, 2002, 19, 73-82.	1.0	57
30	Oscillation-based test in oversampled Î $\hat{\mathfrak{L}}$ î" modulators. Microelectronics Journal, 2002, 33, 799-806.	2.0	19
31	A Simple and Secure Start-Up Circuitry for Oscillation-Based-Test Application. Analog Integrated Circuits and Signal Processing, 2002, 32, 187-190.	1.4	8
32	On-Chip Evaluation of Oscillation-Based-Test Output Signals for Switched-Capacitor Circuits. Analog Integrated Circuits and Signal Processing, 2002, 33, 201-211.	1.4	20
33	A high-Q bandpass fully differential SC filter with enhanced testability. IEEE Journal of Solid-State Circuits, 1998, 33, 976-986.	5.4	20
34	Practical DfT strategy for fault diagnosis in active analogue filters. Electronics Letters, 1995, 31, 1221-1222.	1.0	15
35	Improving the testability of switched-capacitor filters. Analog Integrated Circuits and Signal Processing, 1993, 4, 199-213.	1.4	13
36	Improving the testability of switched-capacitor filters. Journal of Electronic Testing: Theory and Applications (JETTA), 1993, 4, 299-313.	1.2	21

#	Article	IF	CITATIONS
37	Testable switched-capacitor filters. IEEE Journal of Solid-State Circuits, 1993, 28, 719-724.	5.4	52
38	Switch-level fault coverage analysis for switched-capacitor systems. , 0, , .		3
39	Testing mixed-signal cores. , 0, , .		0
40	Design of a switched opamp-based bandpass filter in a 0.35 \hat{l} 4m CMOS technology. , 0, , .		0
41	Practical solutions for the application of the oscillation-based-test: start-up and on-chip evaluation. , 0, , .		3
42	Practical oscillation-based test in analog integrated filters: experimental results. , 0, , .		6